

# TEST REPORT

Report No.: BCTC2303990540-2E

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Applicant: Shenzhen Comiso Digital Technology.,Ltd.

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Product Name: Bluetooth Speaker

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Model/Type Ref.: S55

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Tested Date: 2021-05-17 to 2021-05-21

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Issued Date: 2023-03-20

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**Shenzhen BCTC Testing Co., Ltd.**



Product Name: Bluetooth Speaker  
Trademark: N/A  
Model/Type Ref.: S55  
More models Ref. the 4.1  
Prepared For: Shenzhen Comiso Digital Technology.,Ltd.  
Address: A area of 12/F & B area of 11/F, No, 13 Building, Xiaweishui Industrial Park, Hongqiaotou Community, SongGang Street, Baoan District, Shenzhen City, China  
Manufacturer: Shenzhen Comiso Digital Technology.,Ltd.  
Address: A area of 12/F & B area of 11/F, No, 13 Building, Xiaweishui Industrial Park, Hongqiaotou Community, SongGang Street, Baoan District, Shenzhen City, China  
Prepared By: Shenzhen BCTC Testing Co., Ltd.  
Address: 1-2/F., Building B, Pengzhou Industrial Park, No.158, Fuyuan 1st Road, Zhancheng, Fuhai Subdistrict, Bao'an District, Shenzhen, Guangdong, China  
Sample Received Date: 2021-05-17  
Sample tested Date: 2021-05-17 to 2021-05-21  
Issue Date: 2023-03-20  
Report No.: BCTC2303990540-2E  
Test Standards: ETSI EN 301 489-1 V2.2.3 (2019-11)  
ETSI EN 301 489-17 V3.2.4 (2020-09)  
Test Results: PASS  
Remark: This is RED EMC test report

Tested by:



Eric Yang/Project Handler

Approved by:



Zero Zhou/Reviewer

*The test report is effective only with both signature and specialized stamp. This result(s) shown in this report refer only to the sample(s) tested. Without written approval of Shenzhen BCTC Testing Co., Ltd, this report can't be reproduced except in full. The tested sample(s) and the sample information are provided by the client.*

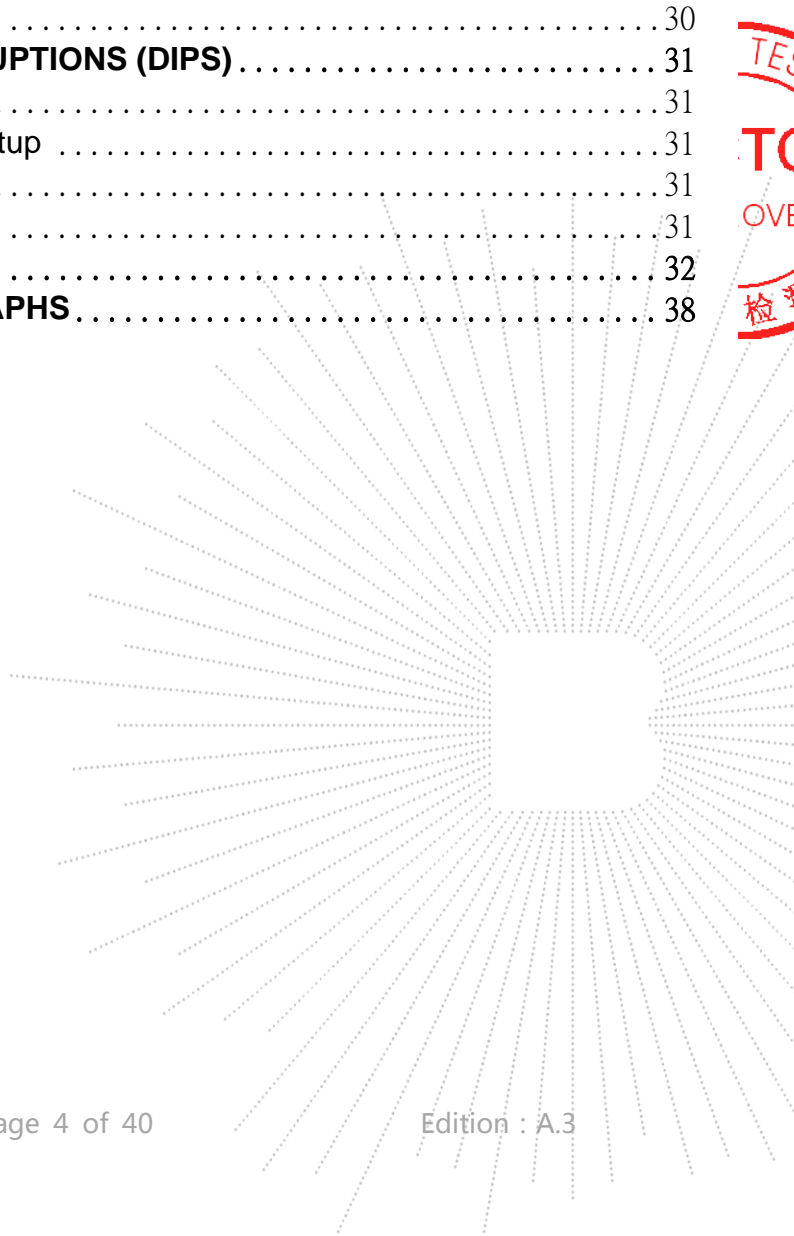
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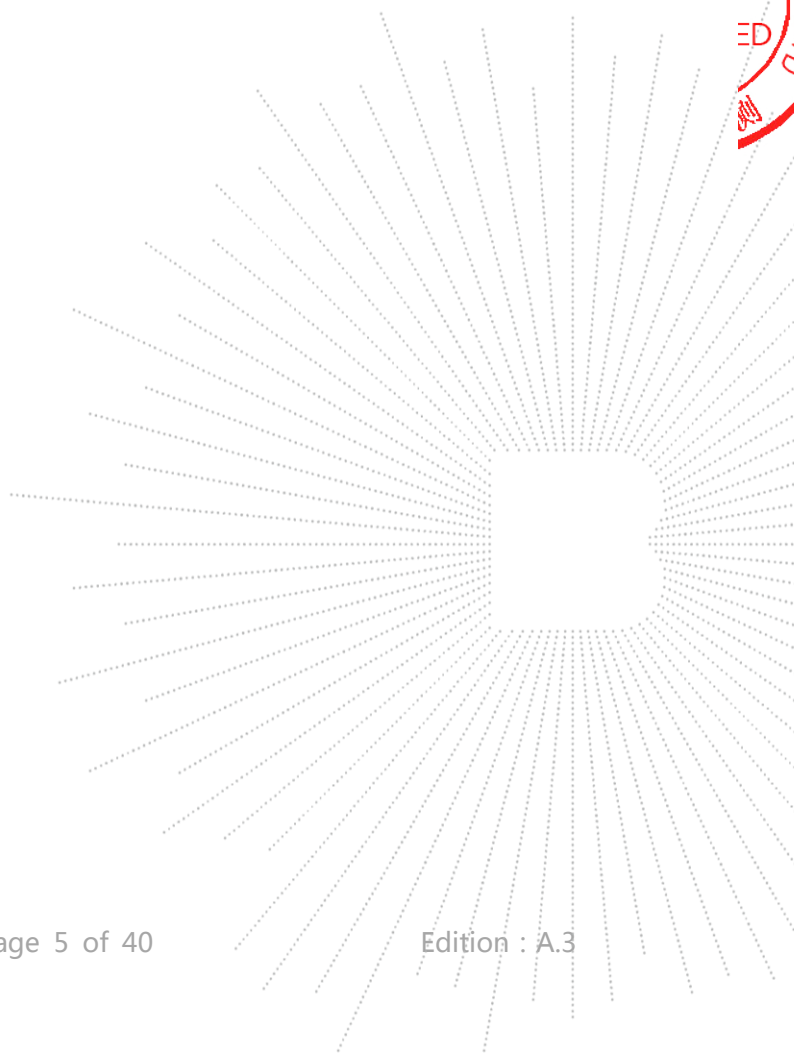
(Note: N/A means not applicable)



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## 1. VERSION

Report No.	Issue Date	Description	Approved
BCTC2303990540-2E	2023-03-20	Original	Valid



## 2. TEST SUMMARY

The Product has been tested according to the following specifications:

EMISSION		
Standard	Test Item	Test result
EN 55032	Conducted emissions from the AC mains power ports	Pass
EN 55032	Asymmetric mode conducted emissions	N/A <sup>1</sup>
EN 55032	Conducted differential voltage emissions	N/A <sup>2</sup>
EN 55032	Radiated emissions	Pass
EN 61000-3-2	Harmonic current emission(H)	N/A <sup>3</sup>
EN 61000-3-3	Voltage fluctuations & flicker(F)	N/A <sup>4</sup>

IMMUNITY		
Standard	Test Item	Test result
IEC 61000-4-2	Electrostatic discharge (ESD)	Pass
IEC 61000-4-3	Continuous RF electromagnetic field disturbances(RS)	Pass
IEC 61000-4-4	Electrical fast transients/burst (EFT)	N/A <sup>4</sup>
IEC 61000-4-5	Surges	N/A <sup>4</sup>
IEC 61000-4-6	Radio frequency, common mode	N/A <sup>4</sup>
IEC 61000-4-11	Voltage dips and interruptions (DIPS)	N/A <sup>4</sup>

Remark:

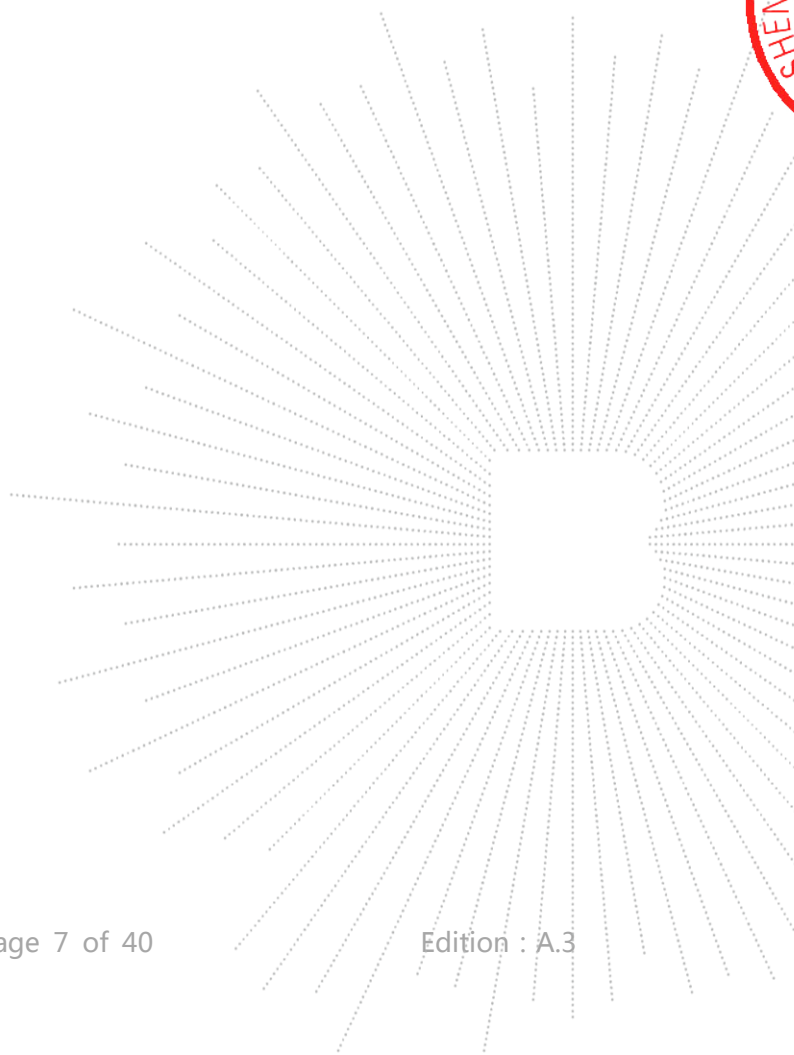
1. Applicable to ports listed above and intended to connect to cables longer than 3 m.
2. The Product has no antenna port.
3. The Product belongs to Class A, and its power is less than 75W, so it deems to fulfil this standard without testing.
4. The EUT is powered by the DC only, the test item is not applicable.

Remark: Based on the following changes in the original test report (BCTC2105800051-2E), No changes were made to the product, Only changes Applicant Company, Applicant Address, Manufacturer Company, Manufacturer Address, Additional models.

### 3. MEASUREMENT UNCERTAINTY

Where relevant, the following measurement uncertainty levels have been estimated for tests performed on the Product as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of  $k=2$ .

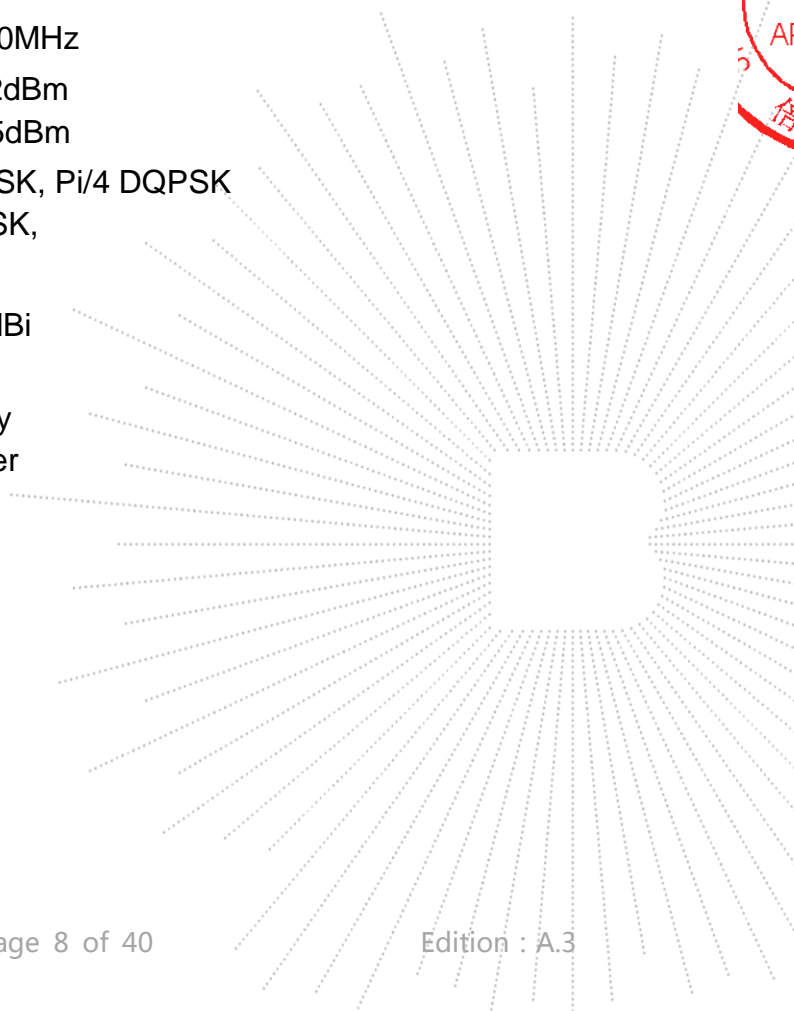
Test item	Value (dB)
Conducted Emission (150kHz-30MHz)	3.20
Radiated Emission(30MHz~1GHz)	4.80
Radiated Emission(1GHz~6GHz)	4.90



## 4. PRODUCT INFORMATION AND TEST SETUP

### 4.1 Product Information

Model/Type Ref.:	S55 S1, S2, S5, S6, S7, S8, S9, S11, S12, S13, S15, S16, S17, S18, S19, S20, S21, S22, S23, S24, S25, S26, S27, S28, S29, S30, S31, S32, S33, S34, S35, S36, S37, S38, S39, S40, S41, S42, S43, S44, S45, S46, S47, S48, S49, S50, S51, S52, S53, S54, S55, S56, S57, S58, S59, S60, S61, S62, S63, S64, S65, S66, S67, S68, S69, S70, S71, S72, S73, S74, Z1, Z2, Z3, Z4, Z5, Z6, Z7, Z8, Z9, Z10, Z11, Z12, Z13, Z14, Z15, Z16, Z17, Z18, Z19, Z20, A1, A2, A3, A4, A5, A6, A7, A8, A9, A10, A11, A12, A13, A14, A15, A16, A17, A18, A19, A20, P1, P2, P3, P4, P5, P6, P7, P8, P9, P10, P11, P12, P13, P14, P15, P16, P17, P18, P19, P20, P21, P22, P23, P24, M68, M88, M71, Platinum Speaker, OPP054
Model differences:	All the model are the same circuit and RF module, except model names.
Hardware Version:	N/A
Software Version:	N/A
Operation Frequency:	Bluetooth: 2402-2480MHz
Max. RF output power:	Bluetooth(EDR):2.32dBm Bluetooth(BLE): 3.15dBm
Type of Modulation:	Bluetooth(EDR): GFSK, Pi/4 DQPSK Bluetooth(BLE): GFSK,
Antenna installation:	Internal antenna
Antenna Gain:	Bluetooth(EDR):0.5dBi Bluetooth(BLE):0dBi
Ratings:	DC 3.7V from Battery DC 5.0V from adapter





## 4.2 Test Setup Configuration

See test photographs attached in EUT TEST SETUP PHOTOGRAPHS for the actual connections between Product and support equipment.

## 4.3 Support Equipment

No	Device	Brand	Model	Series No.	Data Cable	Power
1.	---	---	---	---	---	---

**Notes:**

1. All the equipment/cables were placed in the worst-case configuration to maximize the emission during the test.
2. Grounding was established in accordance with the manufacturer's requirements and conditions for the intended use.

#### 4.4 Test Mode

Test item	Test Mode	Test Voltage
Conducted emissions from the AC mains power ports (150KHz-30MHz) Class B	Charging	DC 5.0V from adapter
	BT Link	DC 3.7V from Battery
Radiated emissions(30MHz-6GHz) Class B	USB Link	DC 3.7V from Battery
	AUX Link	DC 3.7V from Battery
	TF Link	DC 3.7V from Battery
	BT Link	DC 3.7V from Battery
Electrostatic discharge (ESD) <input checked="" type="checkbox"/> HCP & VCP: $\pm 4\text{kV}$ <input checked="" type="checkbox"/> Air Discharge: $\pm 8\text{kV}$ <input checked="" type="checkbox"/> Contact Discharge: $\pm 4\text{kV}$	USB Link	DC 3.7V from Battery
	AUX Link	DC 3.7V from Battery
	TF Link	DC 3.7V from Battery
	BT Link	DC 3.7V from Battery
Continuous RF electromagnetic field disturbances(RS) <input checked="" type="checkbox"/> 80MHz-6000MHz , 3V/m,80% Front, Rear, Left, Right H/V	BT Link	DC 3.7V from Battery
All test mode were tested and passed, only Conducted Emissions, Radiated Emissions shows (*) is the worst case mode which were recorded in this report.		

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## 5. TEST FACILITY AND TEST INSTRUMENT USED

### 5.1 Test Facility

All measurement facilities used to collect the measurement data are located at Shenzhen BCTC Testing Co., Ltd. Address: 1-2/F., Building B, Pengzhou Industrial Park, No.158, Fuyuan 1st Road, Zhancheng, Fuhai Subdistrict, Bao'an District, Shenzhen, Guangdong, China. The site and apparatus are constructed in conformance with the requirements of ANSI C63.4 and CISPR 16-1-1 other equivalent standards.

### 5.2 Test Instrument Used

Conducted emissions Test					
Equipment	Manufacturer	Model#	Serial#	Last Cal.	Next Cal.
Receiver	R&S	ESR3	102075	Jun. 08, 2020	Jun. 07, 2021
LISN	R&S	ENV216	101375	Jun. 04, 2020	Jun. 03, 2021
ISN	HPX	ISN T800	S1509001	Jun. 04, 2020	Jun. 03, 2021
Software	Frad	EZ-EMC	EMC-CON 3A1	\	\

Radiated emissions Test (966 chamber)					
Equipment	Manufacturer	Model#	Serial#	Last Cal.	Next Cal.
966 chamber	ChengYu	966 Room	966	Jun. 06, 2020	Jun. 05, 2023
Receiver	R&S	ESRP	101154	Jun. 08, 2020	Jun. 07, 2021
Receiver	R&S	ESR3	102075	Jun. 08, 2020	Jun. 07, 2021
Amplifier	Schwarzbeck	BBV9718	9718-309	Jun. 04, 2020	Jun. 03, 2021
Amplifier	Schwarzbeck	BBV9744	9744-0037	Jun. 04, 2020	Jun. 03, 2021
TRILOG Broadband Antenna	schwarzbeck	VULB 9163	VULB9163-9 42	Jun. 08, 2020	Jun. 07, 2021
Horn Antenna	SCHWARZB ECK	BBHA9120 D	1541	Jun. 10, 2020	Jun. 09, 2021
Software	Frad	EZ-EMC	FA-03A2 RE	\	\

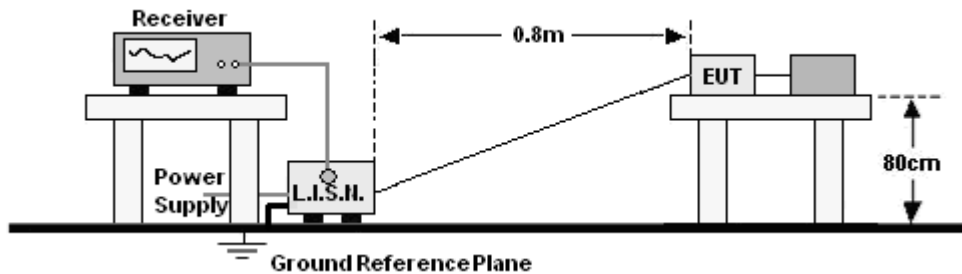
Electrostatic discharge Test					
Equipment	Manufacturer	Model#	Serial#	Last Cal.	Next Cal.
ESD Tester	KIKUSUI	KES4201A	UH002321	Jul. 10, 2020	Jul. 09, 2021

Continuous RF electromagnetic field disturbances Test					
Equipment	Manufacturer	Model#	Serial#	Last Cal.	Next Cal.
Power meter	Keysight	E4419B	GB424214 40	Jun. 08, 2020	Jun. 07, 2021
Power sensor	Keysight	E9 300A	US392113 05	Jun. 08, 2020	Jun. 07, 2021
Power sensor	Keysight	E9 300A	US392116 59	Jun. 08, 2020	Jun. 07, 2021
Amplifier	SKET	HAP_8010 00M-250W	\	Jun. 04, 2020	Jun. 03, 2021
Amplifier	SKET	HAP_0103 G-75W	\	Jun. 04, 2020	Jun. 03, 2021
Amplifier	SKET	HAP_0306 G-50W	\	Jun. 04, 2020	Jun. 03, 2021
Stacked double Log.-Per. Antenna	Schwarzbeck	STLP 9129	077	\	\
Field Probe	Narda	EP-601	80256	Jul. 07, 2020	Jul. 06, 2021
Signal Generator	Agilent	N5181A	MY501437 48	Jun. 04, 2020	Jun. 03, 2021
Software	SKET	EMC-S	1.2.0.18	\	\

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## 6. CONDUCTED EMISSIONS

### 6.1 Block Diagram Of Test Setup



### 6.2 Limit

#### Limits for Conducted emissions at the mains ports of Class B MME

Frequency range (MHz)	Limits dB( $\mu$ V)	
	Quasi-peak	Average
0,15 to 0,50	66 to 56*	56 to 46*
0,50 to 5	56	46
5 to 30	60	50

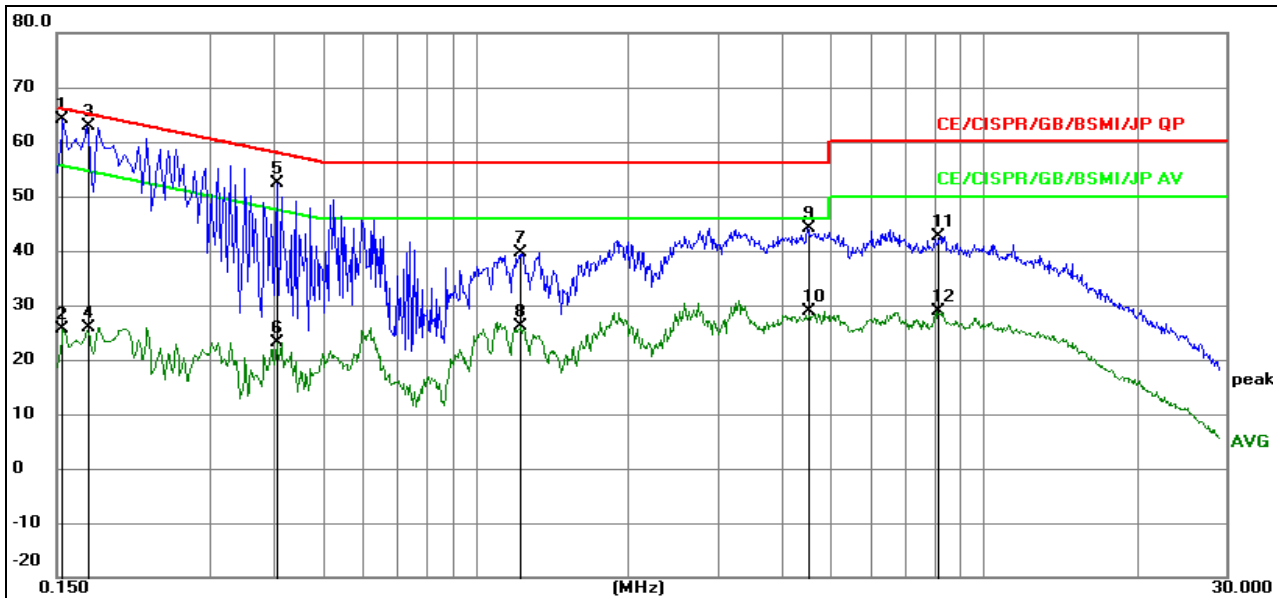
Notes: 1. \*Decreasing linearly with logarithm of frequency.  
2. The lower limit shall apply at the transition frequencies.

### 6.3 Test procedure

- The Product was placed on a nonconductive table 0.8 m above the horizontal ground reference plane, and 0.4 m from the vertical ground reference plane, and connected to the main through Line Impedance Stability Network (L.I.S.N).
- The RBW of the receiver was set at 9 kHz in 150 kHz ~ 30MHz with Peak and AVG detector in Max Hold mode. Run the receiver's pre-scan to record the maximum disturbance generated from Product in all power lines in the full band.
- For each frequency whose maximum record was higher or close to limit, measure its QP and AVG values and record.

### 6.4 Test Result

Temperature:	26 °C	Relative Humidity:	54%
Pressure:	101KPa	Phase :	L
Test Mode	Charging	Remark:	N/A

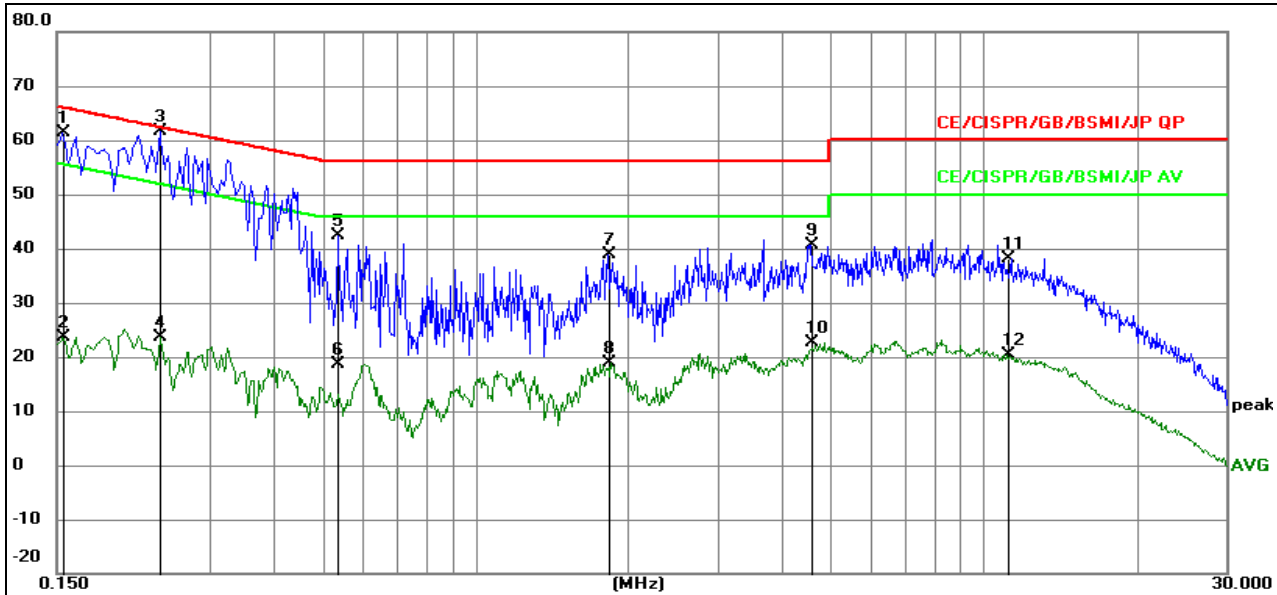


**Remark:**

1. All readings are Quasi-Peak and Average values.
2. Factor = Insertion Loss + Cable Loss.

No.	Mk.	Freq. MHz	Reading Level	Correct Factor dB	Measure- ment dBuV	Limit dBuV	Over dB	Detector
1	*	0.1539	54.55	9.52	64.07	65.79	-1.72	QP
2		0.1539	16.22	9.52	25.74	55.79	-30.05	AVG
3		0.1722	53.32	9.49	62.81	64.85	-2.04	QP
4		0.1722	16.47	9.49	25.96	54.85	-28.89	AVG
5		0.4061	42.93	9.51	52.44	57.73	-5.29	QP
6		0.4061	13.60	9.51	23.11	47.73	-24.62	AVG
7		1.2291	30.04	9.57	39.61	56.00	-16.39	QP
8		1.2291	16.65	9.57	26.22	46.00	-19.78	AVG
9		4.5015	34.47	9.77	44.24	56.00	-11.76	QP
10		4.5015	18.99	9.77	28.76	46.00	-17.24	AVG
11		8.1053	33.04	9.71	42.75	60.00	-17.25	QP
12		8.1053	19.10	9.71	28.81	50.00	-21.19	AVG

Temperature:	26 °C	Relative Humidity:	54%
Pressure:	101KPa	Phase :	N
Test Mode	Charging	Remark:	N/A


**Remark:**

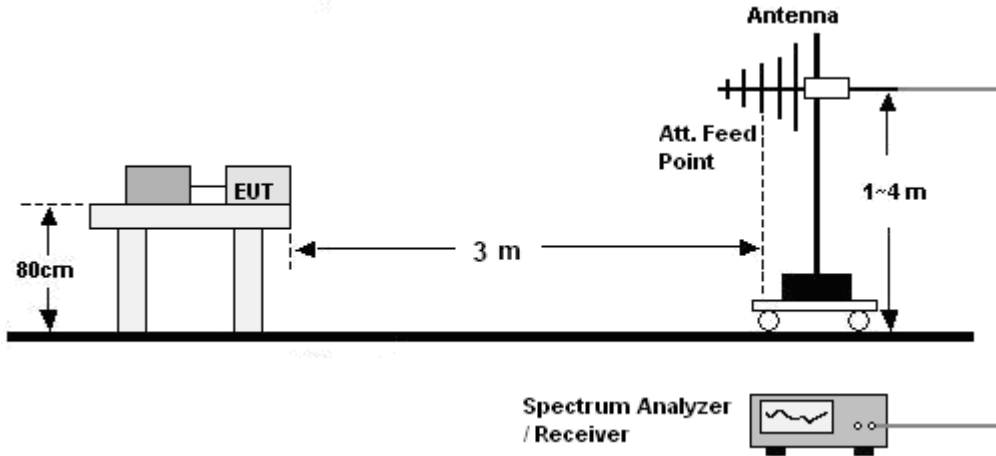
1. All readings are Quasi-Peak and Average values.
2. Factor = Insertion Loss + Cable Loss.

No.	Mk.	Freq.	Reading Level	Correct Factor	Measurement	Limit	Over	Detector
		MHz		dB	dBuV	dBuV	dB	
1		0.1545	51.85	9.51	61.36	65.75	-4.39	QP
2		0.1545	14.22	9.51	23.73	55.75	-32.02	AVG
3	*	0.2400	52.11	9.51	61.62	62.10	-0.48	QP
4		0.2400	14.18	9.51	23.69	52.10	-28.41	AVG
5		0.5370	32.53	9.74	42.27	56.00	-13.73	QP
6		0.5370	8.89	9.74	18.63	46.00	-27.37	AVG
7		1.8240	29.37	9.59	38.96	56.00	-17.04	QP
8		1.8240	9.19	9.59	18.78	46.00	-27.22	AVG
9		4.5825	30.92	9.77	40.69	56.00	-15.31	QP
10		4.5825	12.89	9.77	22.66	46.00	-23.34	AVG
11		11.1885	28.44	9.69	38.13	60.00	-21.87	QP
12		11.1885	10.73	9.69	20.42	50.00	-29.58	AVG

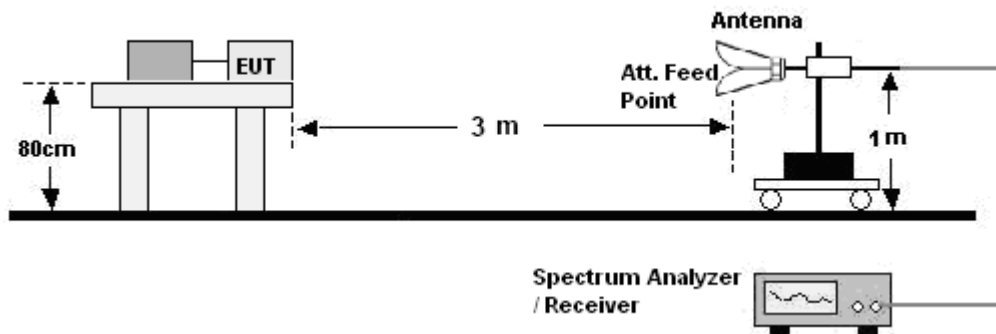
## 7. RADIATED EMISSIONS TEST

### 7.1 Block Diagram Of Test Setup

30MHz ~ 1GHz:



Above 1GHz:



### 7.2 Limits

Limits for radiated disturbance of Class B MME

Frequency (MHz)	Quasi-peak limits at 3m Db(Mv/m)	
30-230	40	
230-1000	47	
Frequency (GHz)	limit above 1G at 3m Db(Mv/m)	
	Average	peak
1-3	50	70
3-6	54	74

**Note:** The lower limit shall apply at the transition frequencies.



### 7.3 Test Procedure

#### **30MHz ~ 1GHz:**

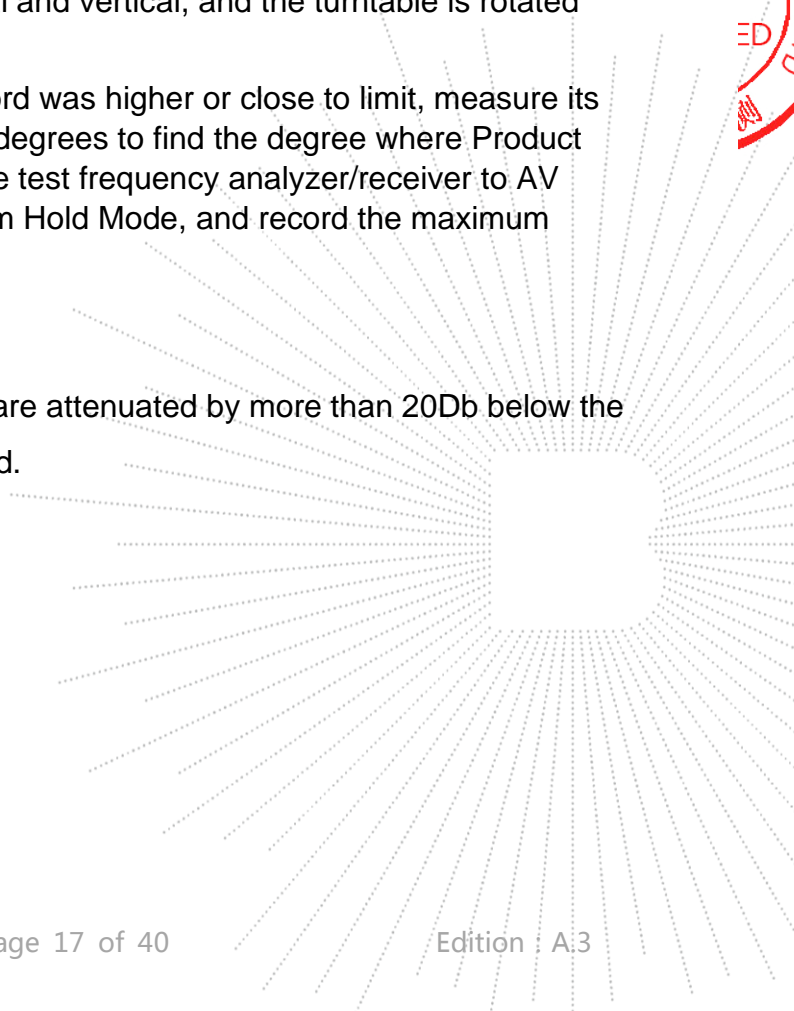
- a. The Product was placed on the nonconductive turntable 0.8 above the ground in a semi anechoic chamber.
- b. Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 120 kHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied between 1~4 m in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- c. For each frequency whose maximum record was higher or close to limit, measure its QP value: vary the antenna's height and rotate the turntable from 0 to 360 degrees to find the height and degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to QP Detector and specified bandwidth with Maximum Hold Mode, and record the maximum value.

#### **Above 1GHz:**

- a. The Product was placed on the non-conductive turntable 0.8 m above the ground in a full anechoic chamber..
- b. Set the spectrum analyzer/receiver in Peak detector, Max Hold mode, and 1MHz RBW. Record the maximum field strength of all the pre-scan process in the full band when the antenna is varied in both horizontal and vertical, and the turntable is rotated from 0 to 360 degrees.
- c. For each frequency whose maximum record was higher or close to limit, measure its AV value: rotate the turntable from 0 to 360 degrees to find the degree where Product radiated the maximum emission, then set the test frequency analyzer/receiver to AV value and specified bandwidth with Maximum Hold Mode, and record the maximum value.

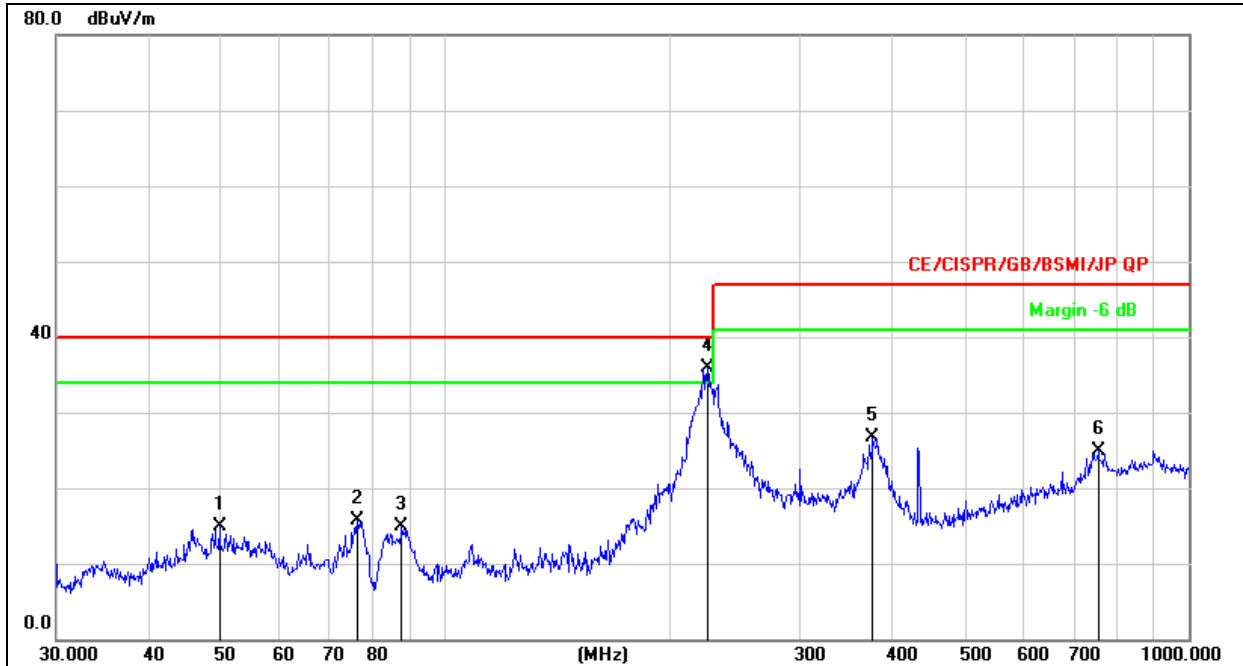
#### **Above 1GHz**

The amplitude of spurious emissions which are attenuated by more than 20Db below the permissible value has no need to be reported.



### 7.4 Test Results

Temperature:	26°C	Relative Humidity:	54%
Pressure:	101KPa	Polarization :	Horizontal
Test Mode	BT	Remark:	N/A



Remark:

Factor = Antenna Factor + Cable Loss – Pre-amplifier.

No. Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV/m	Limit dB/m	Over dB	Detector
1	49.7068	29.05	-14.11	14.94	40.00	-25.06	QP
2	76.2442	34.38	-18.66	15.72	40.00	-24.28	QP
3	87.4177	32.88	-18.01	14.87	40.00	-25.13	QP
4 *	225.3080	50.65	-14.74	35.91	40.00	-4.09	QP
5	375.9385	37.05	-10.35	26.70	47.00	-20.30	QP
6	755.3873	27.54	-2.71	24.83	47.00	-22.17	QP

Temperature:	26°C	Relative Humidity:	54%
Pressure:	101KPa	Polarization :	Vertical
Test Mode	BT	Remark:	N/A



Remark:

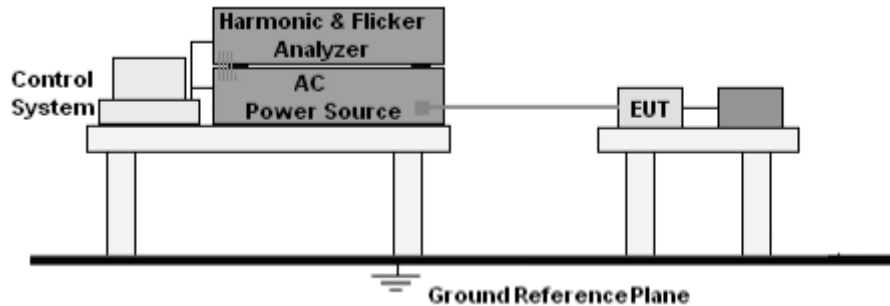
Factor = Antenna Factor + Cable Loss – Pre-amplifier.

No.	Mk.	Freq.	Reading Level	Correct Factor	Measurement	Limit	Over	Detector
		MHz	dBuV	dB	dBuV/m	dB/m	dB	
1		49.8813	32.81	-14.09	18.72	40.00	-21.28	QP
2		124.5690	35.61	-17.06	18.55	40.00	-21.45	QP
3	*	225.2080	50.57	-14.74	35.83	40.00	-4.17	QP
4		378.5842	40.11	-10.28	29.83	47.00	-17.17	QP
5		501.1788	31.71	-7.54	24.17	47.00	-22.83	QP
6		742.2586	27.76	-2.93	24.83	47.00	-22.17	QP

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## 8. HARMONIC CURRENT EMISSION(H)

### 8.1 Block Diagram of Test Setup



### 8.2 Limit

EN 61000-3-2:2014 Clause 7.

### 8.3 Test Procedure

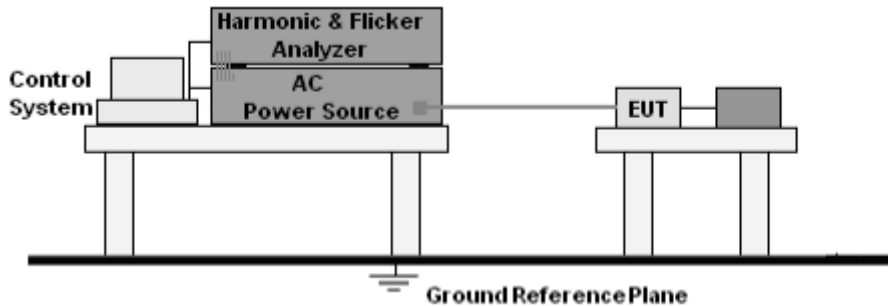
- The Product was placed on the top of a non-conductive table above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.
- The correspondent test program of test instrument to measure the current harmonics emanated from Product was chosen. The measure time shall be not less than the time necessary for the Product to be exercised.

### 8.4 Test Results

The Product belongs to Class A, and its power is less than 75W, so it deems to fulfil this standard without testing.

## 9. VOLTAGE FLUCTUATIONS & FLICKER(F)

### 9.1 Block Diagram of Test Setup



### 9.2 Limit

EN 61000-3-3:2013 Clause 5.

### 9.3 Test Procedure

- The Product was placed on the top of a non-conductive table above the ground and operated to produce the most unfavorable sequence of voltage changes under normal operating conditions.
- During the flick test, the measure time shall include that part of whole operation cycle in which the Product produce the most unfavorable sequence of voltage changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours.

### 9.4 Test Results

The EUT is powered by the DC only, the test item is not applicable.

## 10. IMMUNITY TEST OF GENERAL THE PERFORMANCE CRITERIA

According To EN 301489 -17standard, The General Performance Criteria As Following:

Criteria	During test	After test (i.e. as a result of the application of the test)
A	Shall operate as intended. (see note). Shall be no loss of function. Shall be no unintentional transmissions.	Shall operate as intended. Shall be no degradation of performance. Shall be no loss of function. Shall be no loss of critical stored data.
B	May be loss of function.	Functions shall be self-recoverable. Shall operate as intended after recovering. Shall be no loss of critical stored data.
C	May be loss of function.	Functions shall be recoverable by the operator. Shall operate as intended after recovering. Shall be no loss of critical stored data.

NOTE: Operate as intended during the test allows a level of degradation in accordance with Minimum performance level.

Minimum performance level:

For equipment that supports a PER or FER, the minimum performance level shall be a PER or FER less than or equal to 10 %.

For equipment that does not support a PER or a FER, the minimum performance level shall be no loss of the wireless transmission function needed for the intended use of the equipment.

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**PERFORMANCE FOR TT**

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration, for which performance criteria C shall apply. Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an acknowledgement (ACK) or not-acknowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

**PERFORMANCE FOR TR**

The performance criteria B shall apply, except for voltage dips of 100 ms and voltage interruptions of 5 000 ms duration for which performance criteria C shall apply. Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

**PERFORMANCE FOR CT**

The performance criteria A shall apply. Tests shall be repeated with the EUT in standby mode (if applicable) to ensure that unintentional transmission does not occur. In systems using acknowledgement signals, it is recognized that an Acknowledgement (ACK) or Not Acknowledgement (NACK) transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

**PERFORMANCE FOR CR**

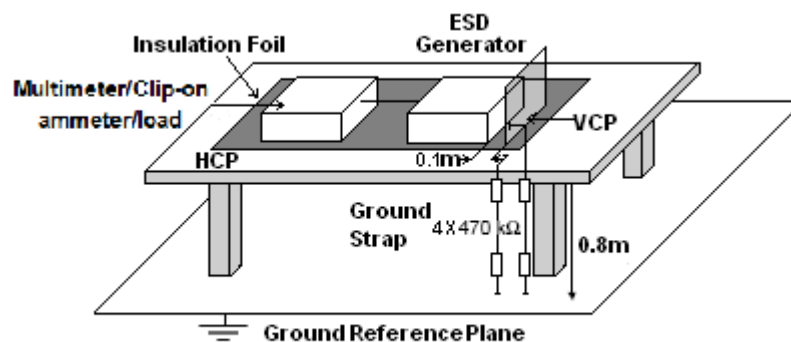
The performance criteria A shall apply. Where the EUT is a transceiver, under no circumstances, shall the transmitter operate unintentionally during the test. In systems using acknowledgement signals, it is recognized that an ACK or NACK transmission may occur, and steps should be taken to ensure that any transmission resulting from the application of the test is correctly interpreted.

## 11. ELECTROSTATIC DISCHARGE (ESD)

### 11.1 Test Specification

<b>Test Port</b>	: Enclosure port
<b>Discharge Impedance</b>	: 330 ohm / 150 pF
<b>Discharge Mode</b>	: Single Discharge
<b>Discharge Period</b>	: one second between each discharge

### 11.2 Block Diagram of Test Setup



### 11.3 Test Procedure

- Electrostatic discharges were applied only to those points and surfaces of the Product that are accessible to users during normal operation.
- The test was performed with at least ten single discharges on the pre-selected points in the most sensitive polarity.
- The time interval between two successive single discharges was at least 1 second.
- The ESD generator was held perpendicularly to the surface to which the discharge was applied and the return cable was at least 0.2 meters from the Product.
- Contact discharges were applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.
- Air discharges were applied with the round discharge tip of the discharge electrode approaching the Product as fast as possible (without causing mechanical damage) to touch the Product. After each discharge, the ESD generator was removed from the Product and re-triggered for a new single discharge. The test was repeated until all discharges were complete.



### 11.4 Test Results

Temperature :	26 °C	Relative Humidity :	54%
Pressure :	101KPa	Test Mode:	BT Link & AUX Link & TF Link & USB Link

Mode	Air Discharge (Test result)								Contact Discharge (Test result)								Perform Criteria	Judgment
	2		4		8		15		2		4		6		8			
Test level (kV)																		
Test Location	+	-	+	-	+	-	+	-	+	-	+	-	+	-	+	-		
HCP									A	A	A	A					TT,TR	PASS
VCP									A	A	A	A					TT,TR	PASS
enclosure	A	A	A	A	A	A			A	A	A	A					TT,TR	PASS
Keys	A	A	A	A	A	A											TT,TR	PASS

Note:

- 1) P/N denotes the Positive/Negative polarity of the output voltage.
- 2) Test condition:  
 Direct / Indirect (HCP/VCP) discharges: Minimum 50 times (Positive/Negative) at each point. Air discharges: Minimum 10 times (Positive/Negative) at each point.
- 3) N/A - denotes test is not applicable in this test report
- 4) There was not any unintentional transmission in standby mode



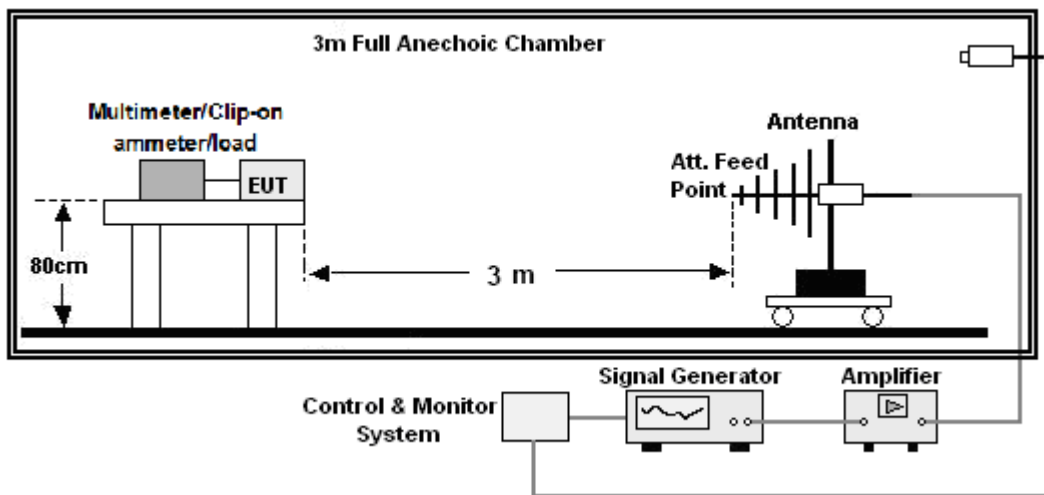
## 12. CONTINUOUS RF ELECTROMAGNETIC FIELD DISTURBANCES(RS)

### 12.1 Test Specification

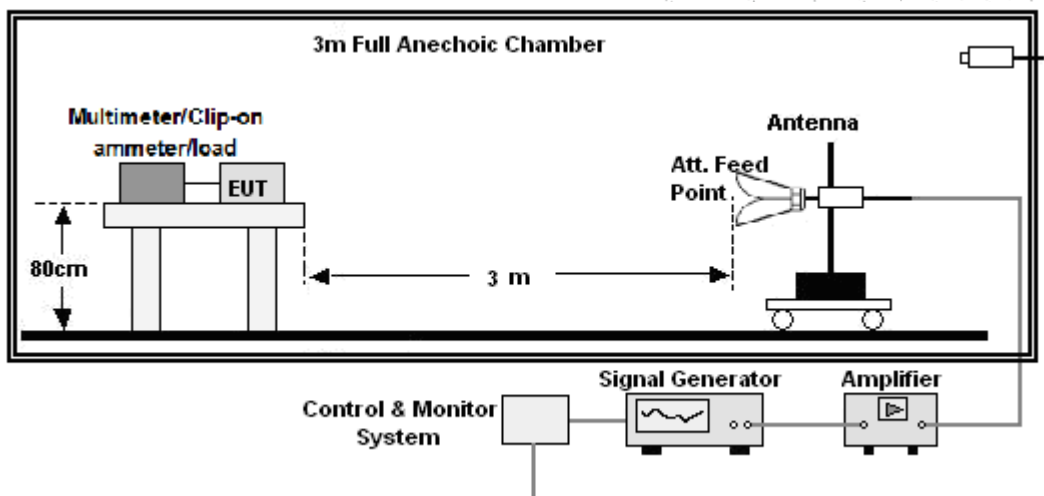
<b>Test Port</b>	: Enclosure port
<b>Step Size</b>	: 1%
<b>Modulation</b>	: 1kHz, 80% AM
<b>Dwell Time</b>	: 1 second
<b>Polarization</b>	: Horizontal & Vertical

### 12.2 Block Diagram of Test Setup

Below 1GHz:



Above 1GHz:



### 12.3 Test Procedure

- a. The testing was performed in a fully-anechoic chamber. The transmit antenna was located at a distance of 3 meters from the Product.
- b. The frequency range is swept from 80MHz to 6000MHz, with the signal 80% amplitude modulated with a 1 kHz sine wave, and the step size was 1%.
- c. The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised and to be able to respond, but should not exceed 5 s at each of the frequencies during the scan.
- d. The test was performed with the Product exposed to both vertically and horizontally polarized fields on each of the four sides.
- e. For Broadcast reception function: Group 2 not apply in this test.

### 12.4 Test Results

Temperature :	26 °C	Relative Humidity :	54%
Pressure :	101KPa	Test Mode:	BT Link

Frequency Range (MHz)	RF Field Position	R.F. Field Strength	Azimuth	Perform Criteria	Test Result	Judgment
80~6000	H / V	3 V/m (rms) AM Modulated 1000Hz, 80%	Front	CT,CR	A	PASS
			Rear			
			Left			
			Right			

Note:

- 1) P/N denotes the Positive/Negative polarity of the output voltage.
- 2) N/A - denotes test is not applicable in this test report.
- 3) There was no change operated with initial operating during the test.
- 4) There was not any unintentional transmission in standby mode

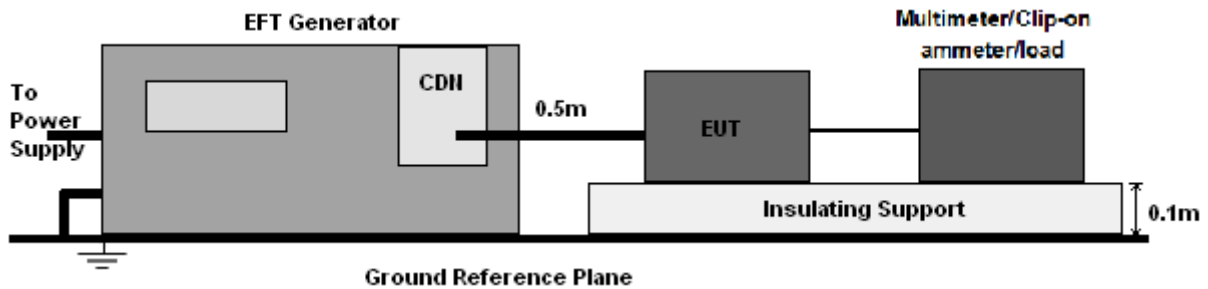
## 13. ELECTRICAL FAST TRANSIENTS/BURST (EFT)

### 13.1 Test Specification

<b>Test Port</b>	: input AC / DC power port
<b>Impulse Frequency</b>	: 5 kHz
<b>Impulse Wave-shape</b>	: 5/50 ns
<b>Burst Duration</b>	: 15 ms
<b>Burst Period</b>	: 300 ms
<b>Test Duration</b>	: 2 minutes per polarity

### 13.2 Block Diagram of EUT Test Setup

For input AC / DC power port:



### 13.3 Test Procedure

- The Product and support units were located on a non-conductive table above ground reference plane.
- A 0.5m-long power cord was attached to Product during the test.

### 13.4 Test Results

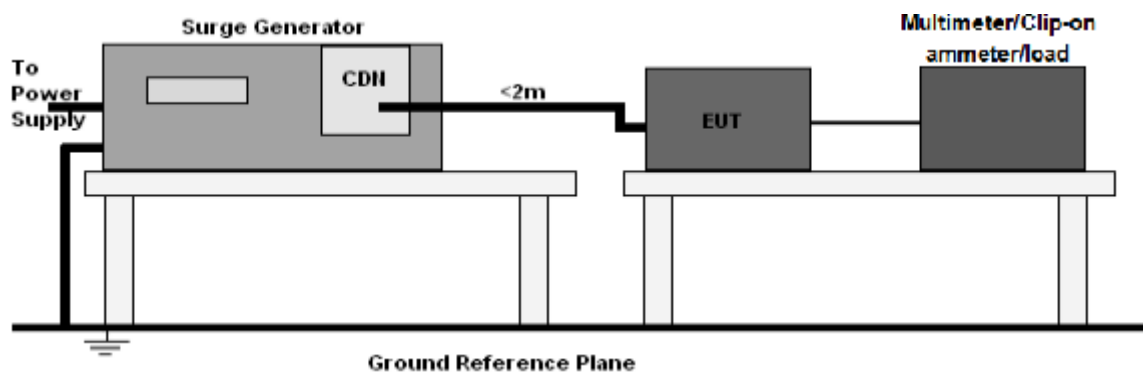
The EUT is powered by the DC only, the test item is not applicable.

## 14. SURGES IMMUNITY TEST

### 14.1 Test Specification

<b>Test Port</b>	: input AC / DC power port
<b>Wave-Shape</b>	: Open Circuit Voltage - 1.2 / 50 us Short Circuit Current - 8 / 20 us
<b>Pulse Repetition Rate</b>	: 1 pulse / min.
<b>Phase Angle</b>	: 0° / 90° / 180° / 270°
<b>Test Events</b>	: 5 pulses (positive & negative) for each polarity

### 14.2 Block Diagram of EUT Test Setup



### 14.3 Test Procedure

- The surge is to be applied to the Product power supply terminals via the capacitive coupling network. Decoupling networks are required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines, and to provide sufficient decoupling impedance to the surge wave.
- The power cord between the Product and the coupling/decoupling networks shall be 2 meters in length (or shorter). Interconnection line between the Product and the coupling/decoupling networks shall be 2 meters in length (or shorter).

### 14.4 Test Result

The EUT is powered by the DC only, the test item is not applicable.

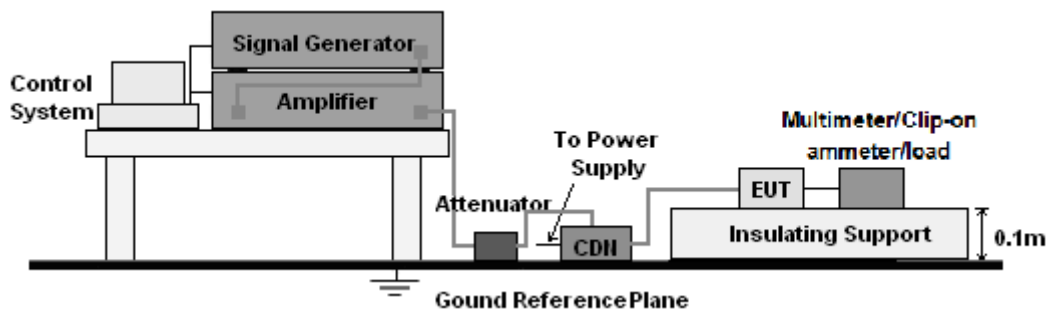
## 15. CONTINUOUS INDUCED RF DISTURBANCES (CS)

### 15.1 Test Specification

<b>Test Port</b>	: input AC / DC power port
<b>Step Size</b>	: 1%
<b>Modulation</b>	: 1kHz, 80% AM
<b>Dwell Time</b>	: 1 second

### 15.2 Block Diagram of EUT Test Setup

For input AC / DC power port:



### 15.3 Test Procedure

For input AC/ DC power port:

- The Product and support units were located at a ground reference plane with the interposition of a 0.1 m thickness insulating support and the CDN was located on GRP directly.
- The frequency range is swept from 150 kHz to 10MHz, 10MHz to 30MHz, 30MHz to 80MHz with the signal 80% amplitude modulated with a 1 kHz sine wave, and the step size was 1% of fundamental.
- The dwell time at each frequency shall be not less than the time necessary for the Product to be able to respond.

### 15.4 Test Result

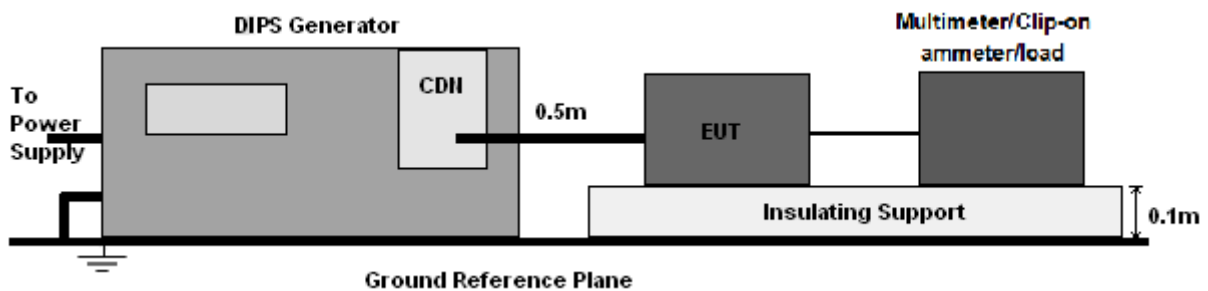
The EUT is powered by the DC only, the test item is not applicable.

## 16. VOLTAGE DIPS AND INTERRUPTIONS (DIPS)

### 16.1 Test Specification

<b>Test Port</b>	: input AC power port
<b>Phase Angle</b>	: 0°, 180°
<b>Test cycle</b>	: 3 times

### 16.2 Block Diagram of EUT Test Setup



### 16.3 Test Procedure

- The Product and support units were located on a non-conductive table above ground floor.
- Set the parameter of tests and then perform the test software of test simulator.
- Conditions changes to occur at 0 degree crossover point of the voltage waveform.

### 16.4 Test Result

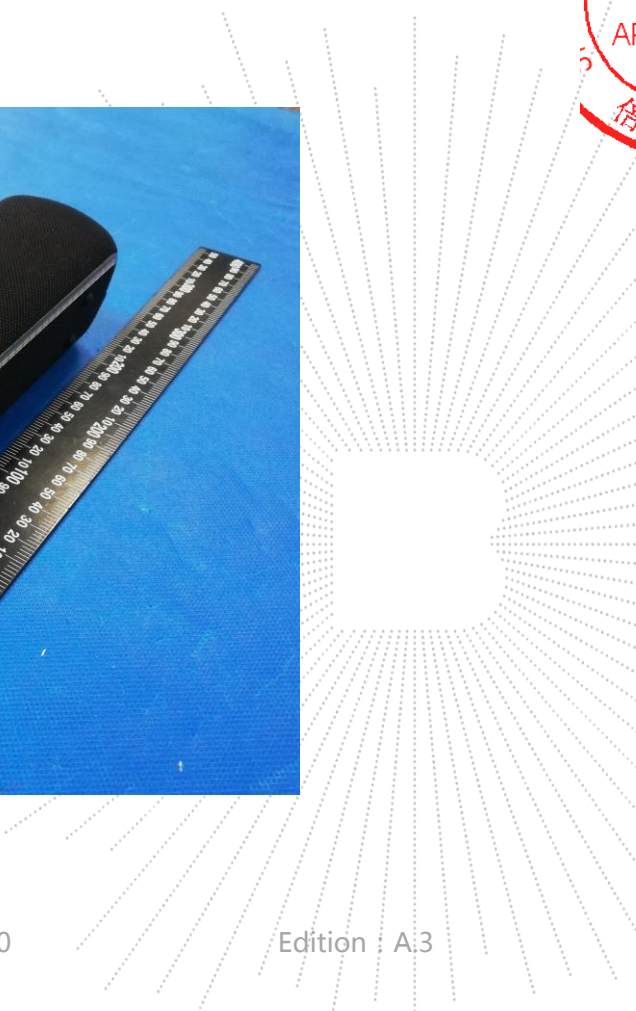
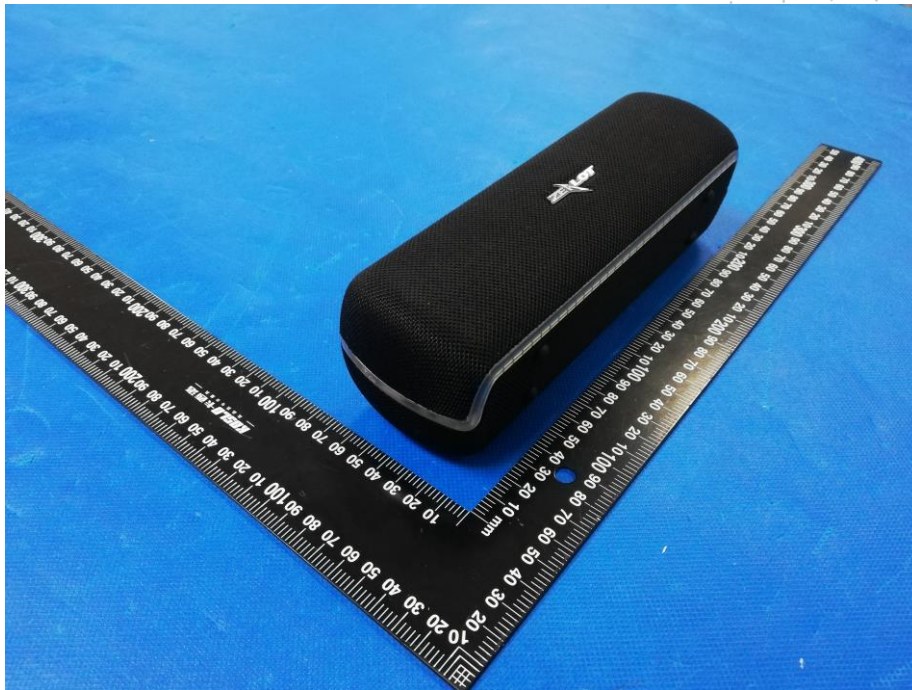
The EUT is powered by the DC only, the test item is not applicable.

## 17. EUT PHOTOGRAPHS

EUT Photo 1

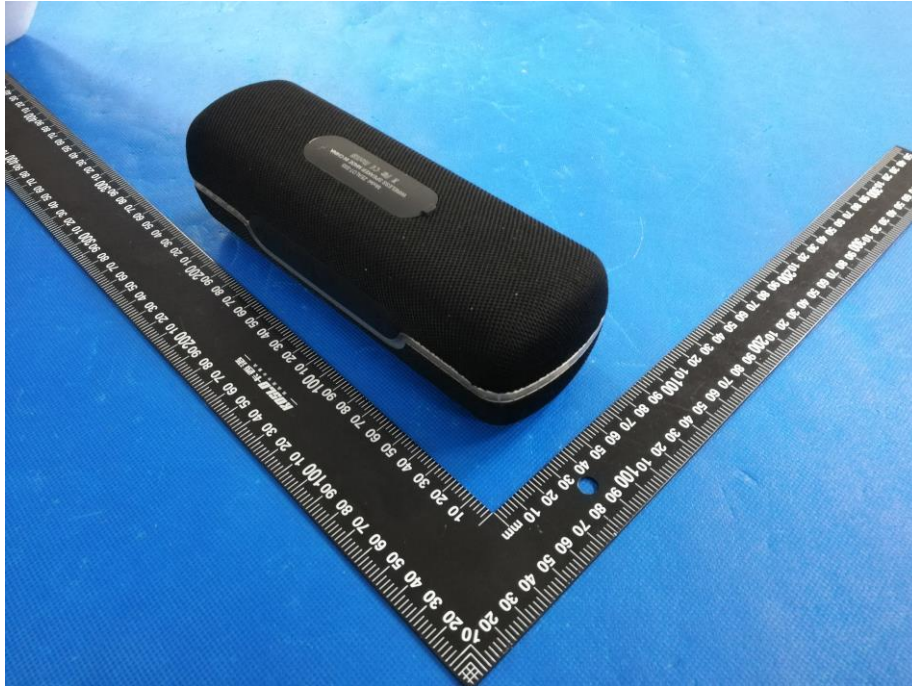


EUT Photo 2

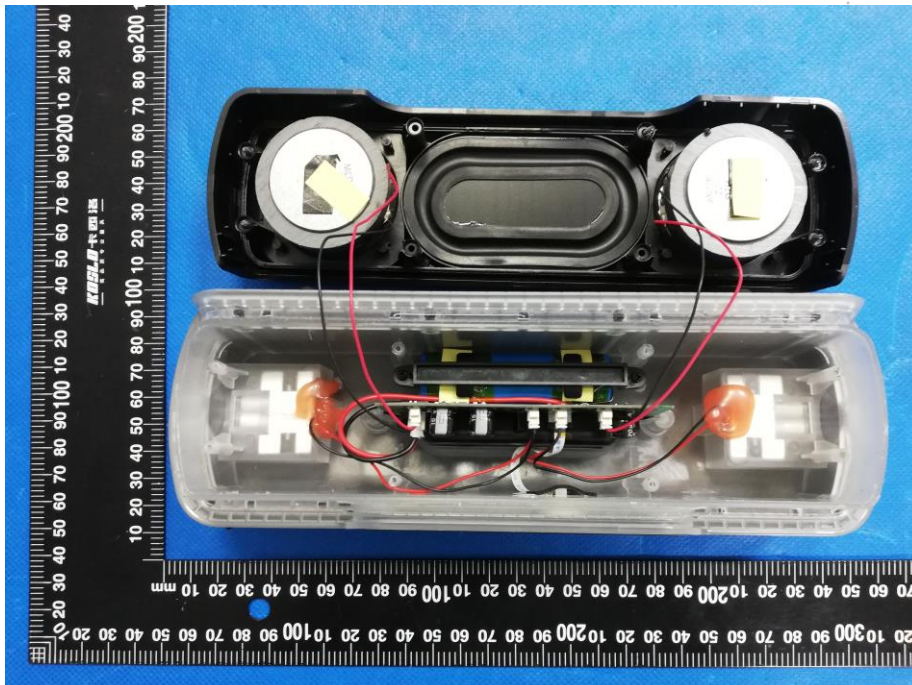




**EUT Photo 3**

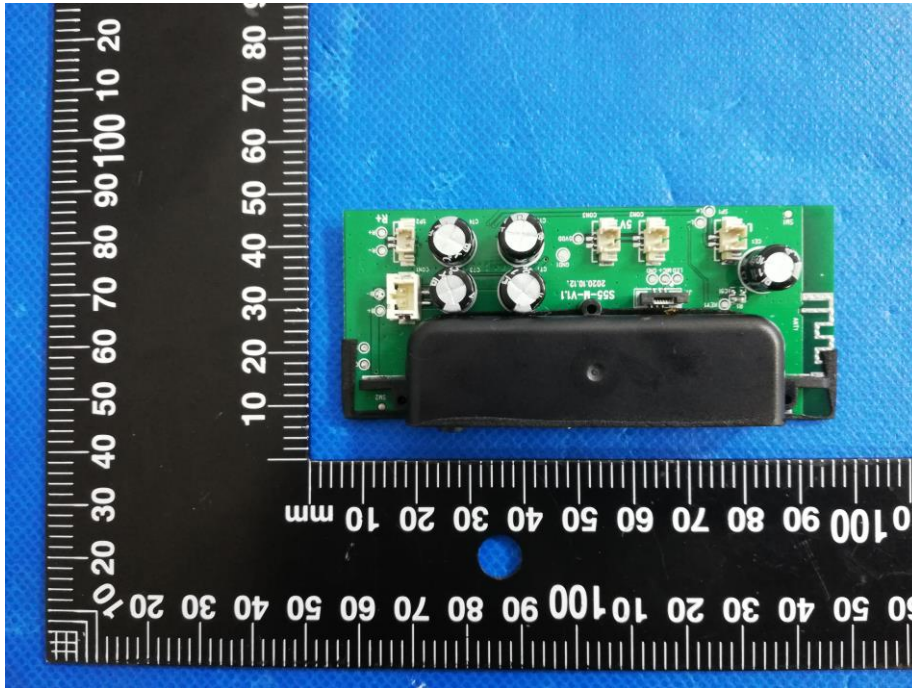


**EUT Photo 4**

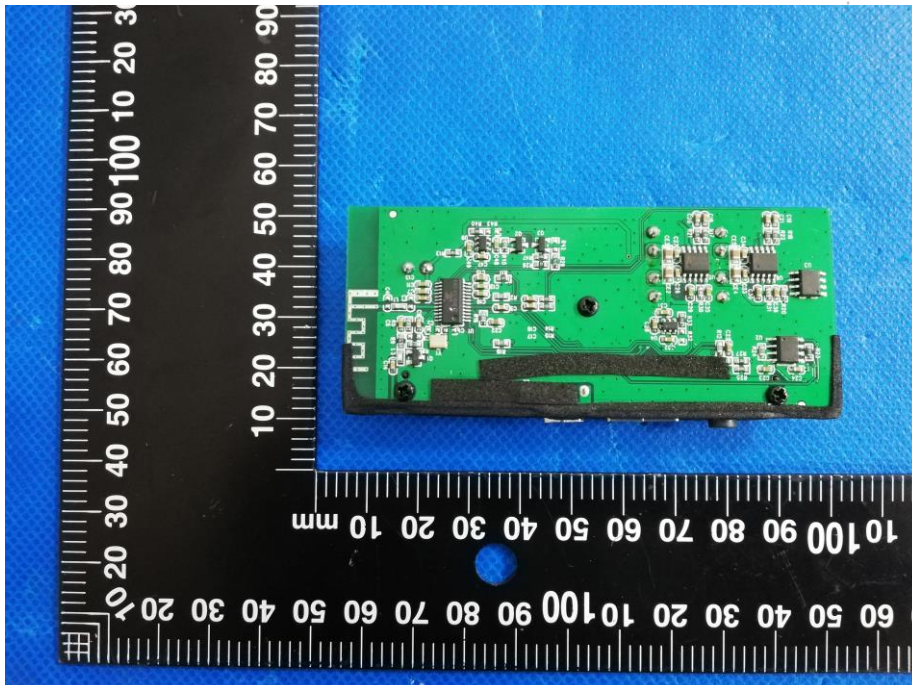


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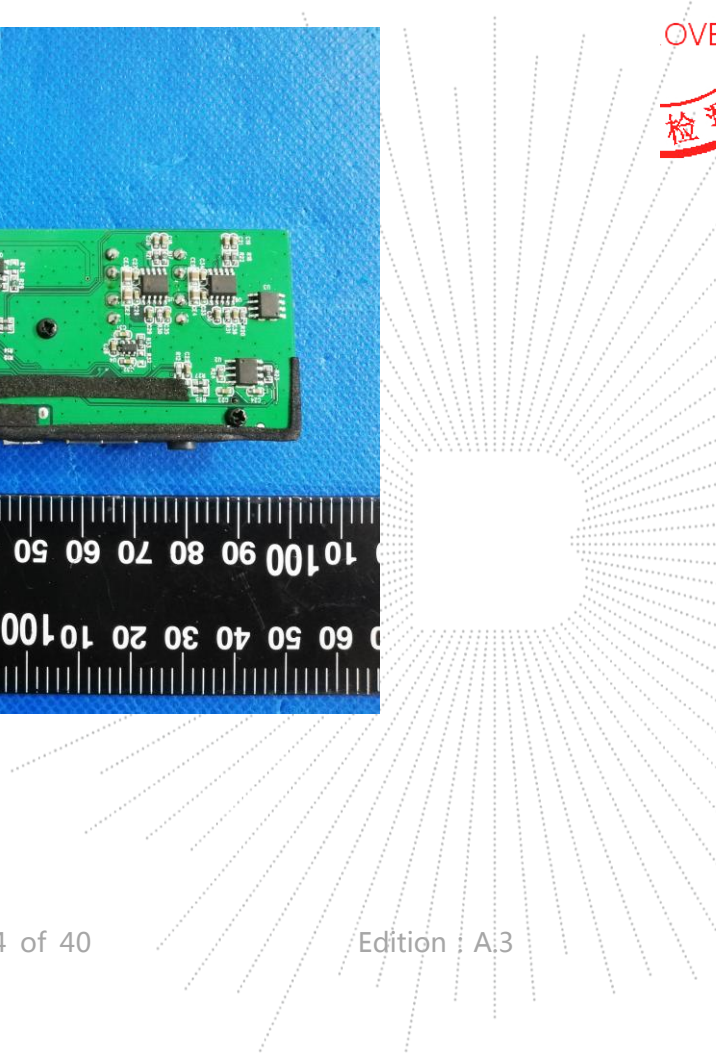
**EUT Photo 5**



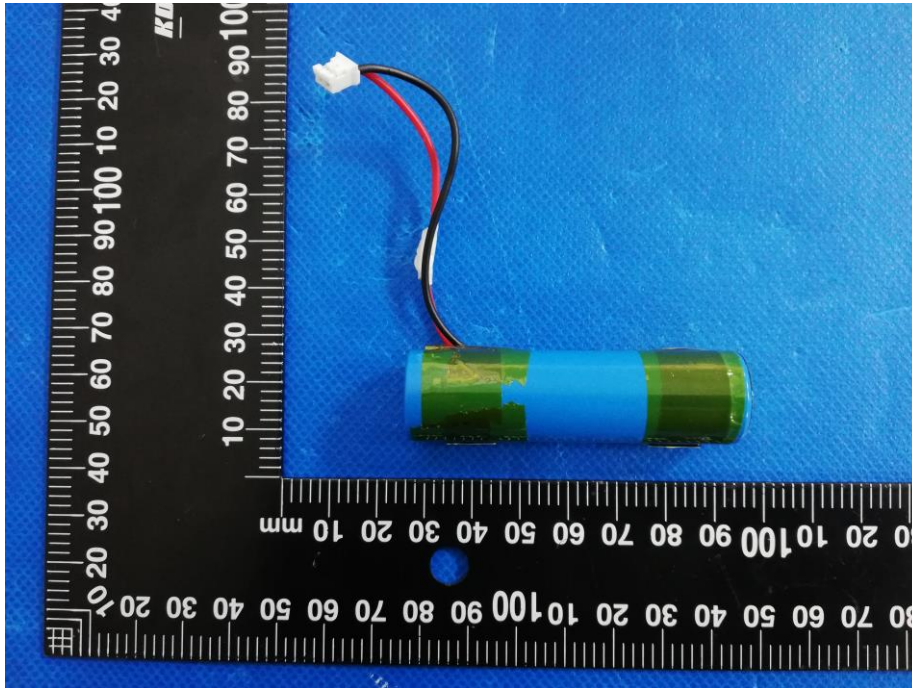
**EUT Photo 6**



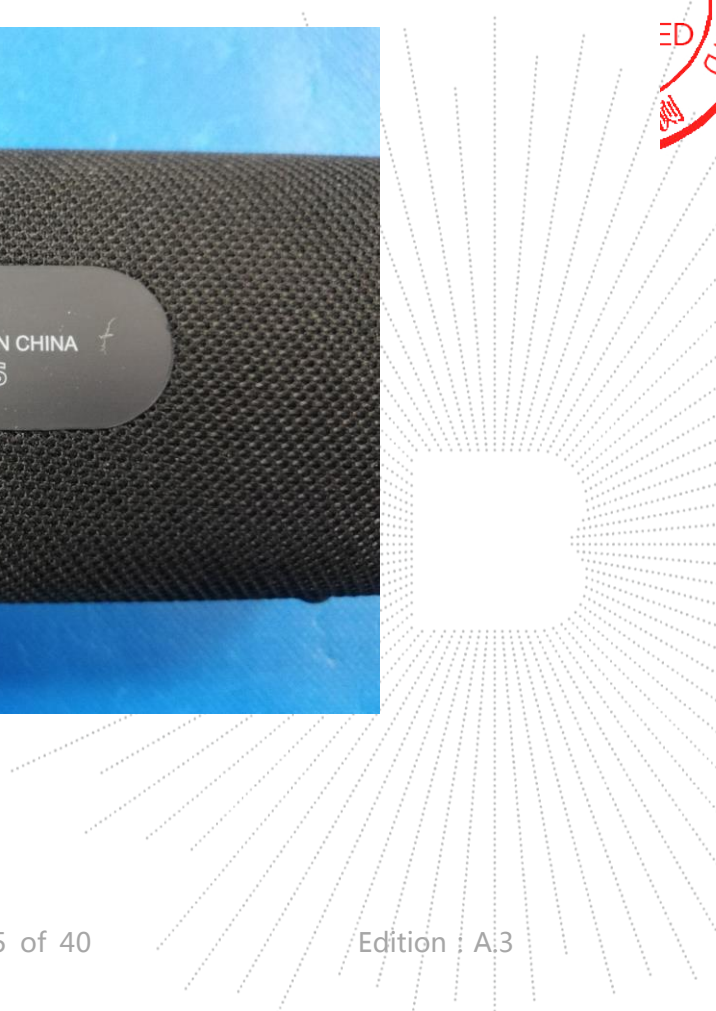
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**EUT Photo 7**



**EUT Photo 8**



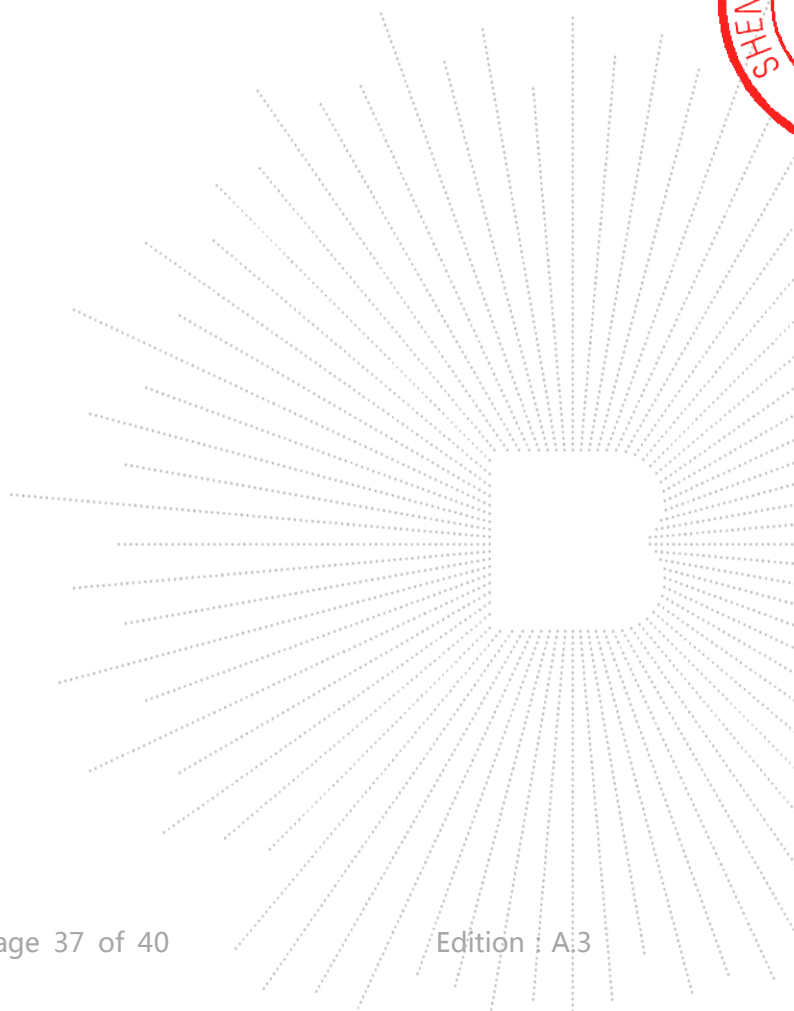
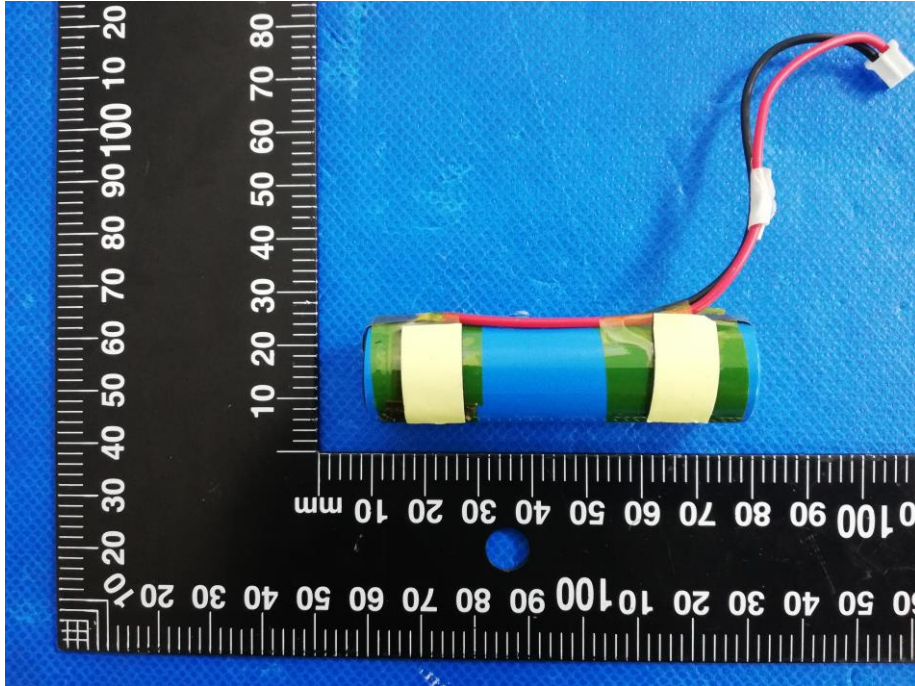
**EUT Photo 9**



**EUT Photo 10**



**EUT Photo 11**

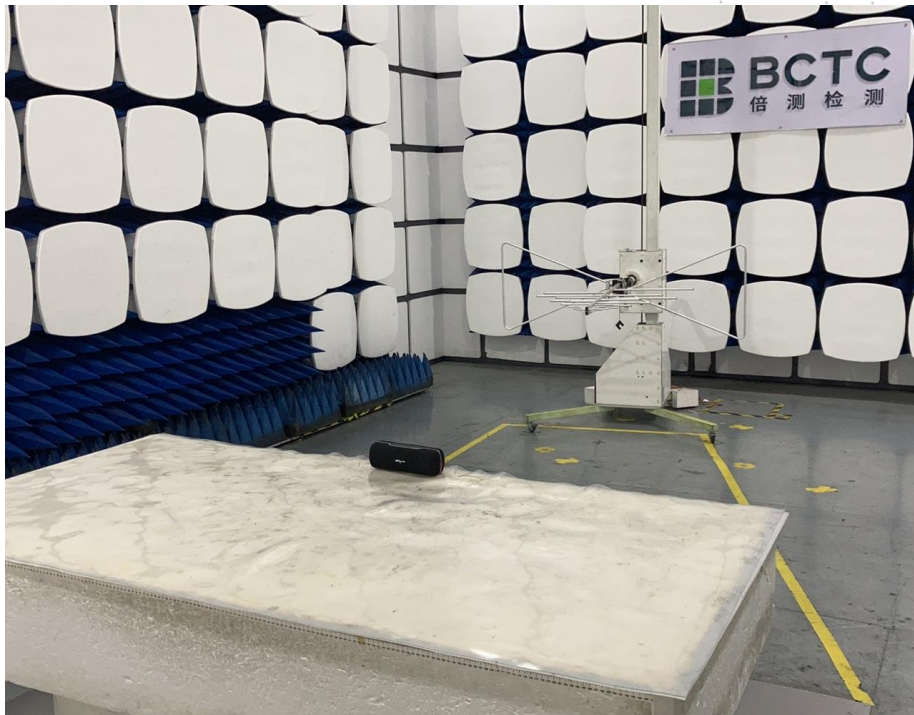


## 18. EUT TEST SETUP PHOTOGRAPHS

Conducted emissions



Radiated emissions



BCTC  
BC  
APPR  
停测

ESD



RS



TEST  
TC  
OVED  
检测

**STATEMENT**

1. The equipment lists are traceable to the national reference standards.
2. The test report can not be partially copied unless prior written approval is issued from our lab.
3. The test report is invalid without the "special seal for inspection and testing".
4. The test report is invalid without the signature of the approver.
5. The test process and test result is only related to the Unit Under Test.
6. Sample information is provided by the client and the laboratory is not responsible for its authenticity.
7. The test report without CMA mark is only used for scientific research, teaching, enterprise product development and internal quality control purposes.
8. The quality system of our laboratory is in accordance with ISO/IEC17025.
9. If there is any objection to this test report, the client should inform issuing laboratory within 15 days from the date of receiving test report.

## Address:

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